

<b>Notice of References Cited</b>	Application/Control No. 10/801,575		Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0177978	08-2005	Satoh et al.	016/319
*	B	US-2004/0127269	07-2004	Nonaka, Keisuke	455/575.3
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	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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